

Application/Control No.	Applicant(s)/Patent under Reexamination
10/017,471	TAKANO ET AL.
Examiner	Art Unit
Nashaat T. Nashed, Ph. D.	1656

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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interference	search for e of SEQ ID and 19.	1/4/2006 1/19/06	NASH	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST Search, enclosed.	1/17/2006	NASH		